

Microscopy TODAY

Volume 25 Number 4 2017 July



75 years
1942-2017
MSA
Microscopy Society of America



MAS **50**
Microanalysis Society YEARS



ifes Microscopy
international field emission society
50 Years of Atom Probe
TODAY
25 Years

The All-New ArBlade 5000

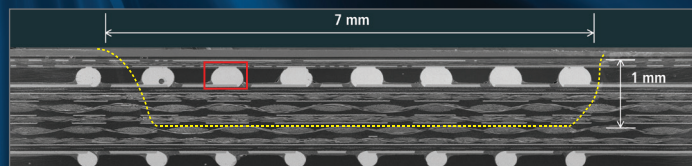
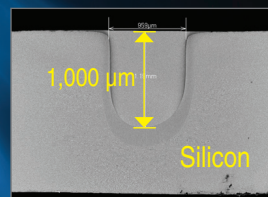
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programming in honor of



and



as well as
the 50th
anniversary of
the atom probe



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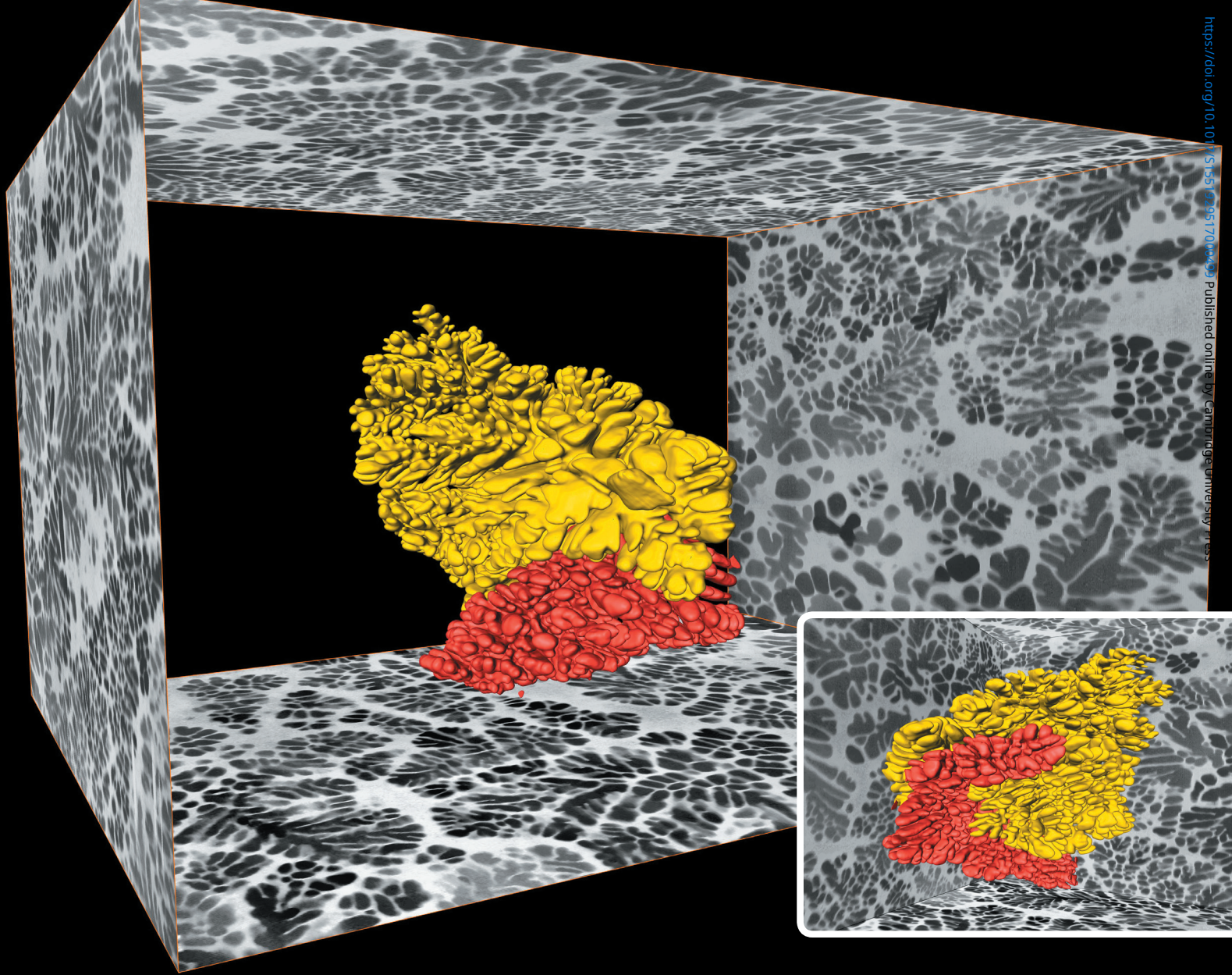
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FEI Avizo® 3D visualization of two large adjacent crystalline dendrites of a bulk-metallic-glass matrix composite ($Zr_{58.5}Ti_{14.3}Nb_{5.2}Cu_{6.1}Ni_{4.9}Be_{10}$). Data was obtained by large volume serial sectioning tomography using the Helios PFIB DualBeam. The sectioned block is about $90 \times 80 \times 70 \mu m^3$. Sample from The University of Tennessee, USA. Images courtesy of The University of Manchester.

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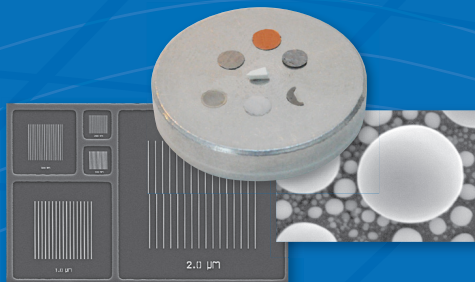


Logos of organizations celebrating anniversaries this year.

ACCESSORIES, STANDARDS & CONSUMABLES

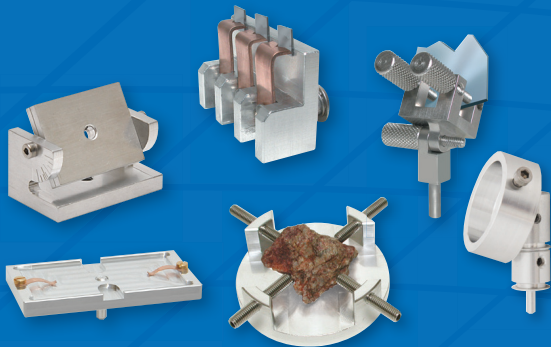


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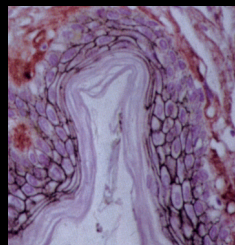
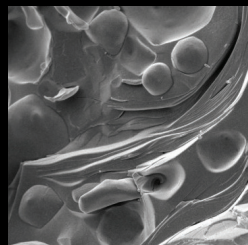
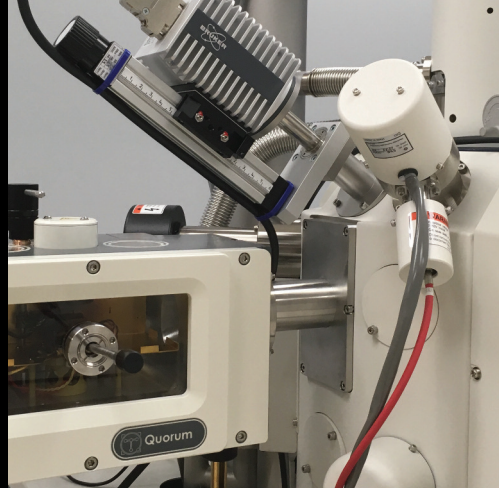
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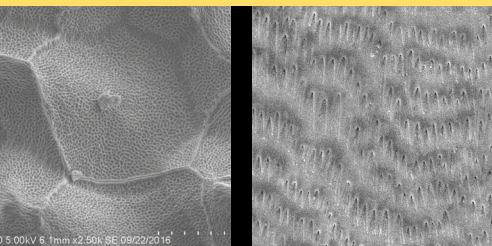
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